

## TP5510 Full Duplex Analog Front End (AFE) for Consumer Applications

### General Description

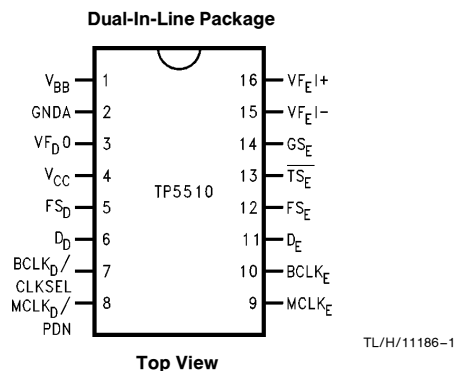
The TP5510 consists of a  $\mu$ -law monolithic AFE device utilizing the A/D and D/A conversion architecture shown in *Figure 1*, and a serial data interface. The device is fabricated using National's advanced double-poly CMOS process (microCMOS).

The A/D portion of the device consists of an input gain adjust amplifier, an active RC pre-filter which eliminates very high frequency noise, and a switched-capacitor band-pass filter that rejects signals below 200 Hz and above 3400 Hz. Also included are auto-zero circuitry and a compressing A/D which samples the filtered signal and converts it to the  $\mu$ -law digital format. The decode portion of the device consists of an expanding D/A, which reconstructs the analog signal from the compressed  $\mu$ -law code, a low-pass filter which corrects for the sin x/x response of the D/A output and rejects signals above 3400 Hz, followed by a single-ended power amplifier capable of driving low impedance loads. The device requires a 1.536 MHz, 1.544 MHz or 2.048 MHz master clock, bit clocks which may vary from 64 kHz to 2.048 MHz; and 8 kHz frame sync pulses.

### Features

- Complete A/D and D/A with filter system including:
  - Serial Data Interface
  - Encode high-pass and low-pass filter
  - Decode low-pass filter with sin x/x correction
  - Active RC noise filters
  - $\mu$ -law compatible A/D and D/A
  - Internal precision voltage reference
  - Internal auto-zero circuitry
- $\mu$ -law—TP5510
- $\pm 5V$  operation
- Low operating power—typically 60 mW
- Power-down standby mode—typically 3 mW
- Automatic power-down
- TTL or CMOS compatible digital interfaces
- Maximizes PC card circuit density
- Plastic DIP and SOIC packages
- 8-bit digital I/O
- 13-bit dynamic range
- Use with DSP processor
- Applications: Tapeless Answering Machines, Cordless Phones, Cellular Radio

### Connection Diagram



**Order Number TP5510WM**  
**See NS Package Number M16B**

**Order Number TP5510N**  
**See NS Package Number N16A**

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## Block Diagram

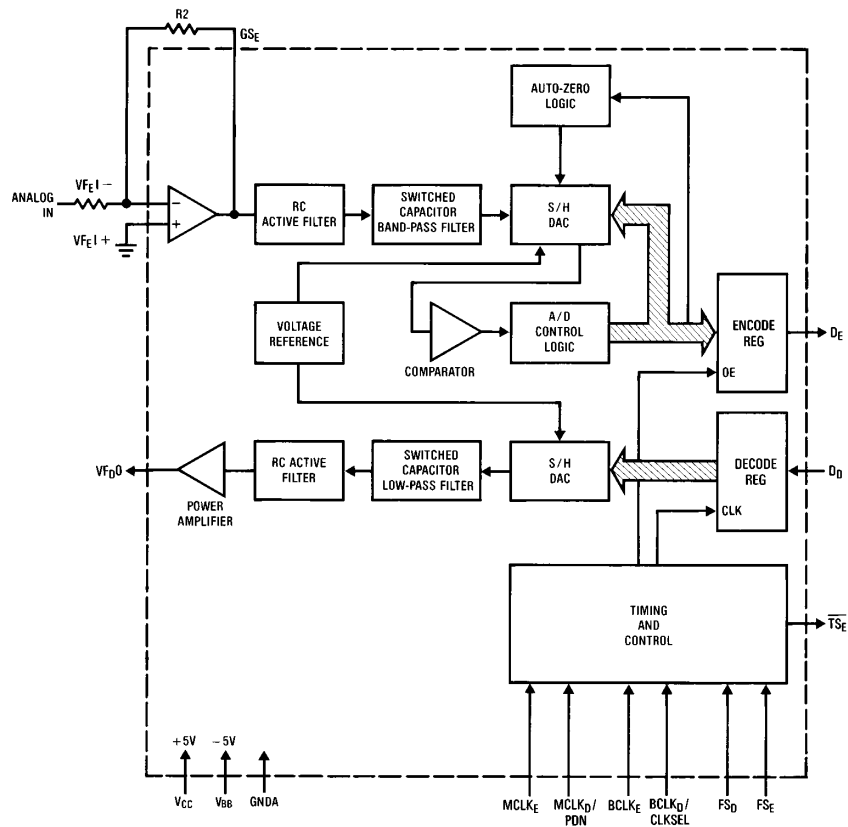


FIGURE 1

TL/H/11186-2

## Pin Description

Symbol	Function	Symbol	Function
$V_{BB}$	Negative power supply pin. $V_{BB} = -5V \pm 5\%$ .	$FS_D$	Decode frame sync pulse which enables $BCLK_R$ to shift data into $D_D$ . $FS_D$ is an 8 kHz pulse train. See <i>Figures 2 and 3</i> for timing details.
GNDA	Analog ground. All signals are referenced to this pin.	$D_D$	Decode data input. Data is shifted into $D_D$ following the $FS_D$ leading edge.
$VF_{D0}$	Analog output of the receive power amplifier.	$BCLK_D/CLKSEL$	The bit clock which shifts data into $D_D$ after the $FS_D$ leading edge. May vary from 64 kHz to 2.048 MHz. Alternatively, may be a logic input which selects either 1.536 MHz/1.544 MHz or 2.048 MHz for master clock in synchronous mode and $BCLK_D$ is used for both encode and decode directions (see Table 1).
$V_{CC}$	Positive power supply pin. $V_{CC} = +5V \pm 5\%$ .		

## Pin Description (Continued)

Symbol	Function
MCLK <sub>D</sub> /PDN	Encode master clock. Must be 1.536 MHz, 1.544 MHz or 2.048 MHz. May be asynchronous with MCLK <sub>E</sub> , but should be synchronous with MCLK <sub>E</sub> for best performance. When MCLK <sub>D</sub> is connected continuously low, MCLK <sub>E</sub> is selected for all internal timing. When MCLK <sub>D</sub> is connected continuously high, the device is powered down.
MCLK <sub>E</sub>	Encode master clock. Must be 1.536 MHz, 1.544 MHz or 2.048 MHz. May be asynchronous with MCLK <sub>D</sub> . Best performance is realized from synchronous operation.
FS <sub>E</sub>	Encode frame sync pulse input which enables BCLK <sub>E</sub> to shift out the data on D <sub>E</sub> . FS <sub>E</sub> is an 8 kHz pulse train, see <i>Figures 2</i> and <i>3</i> for timing details.
BCLK <sub>E</sub>	The bit clock which shifts out the data on D <sub>E</sub> . May vary from 64 kHz to 2.048 MHz, but must be synchronous with MCLK <sub>E</sub> .
D <sub>E</sub>	The TRI-STATE® data output which is enabled by FS <sub>E</sub> .
TS <sub>E</sub>	Open drain output which pulses low during the A/D time slot.
GS <sub>E</sub>	Analog output of the encode input amplifier. Used to externally set gain.
VF <sub>E</sub> I <sup>-</sup>	Inverting input of the encode input amplifier.
VF <sub>E</sub> I <sup>+</sup>	Non-inverting input of the encode input amplifier.

## Functional Description

### POWER-UP

When power is first applied, power-on reset circuitry initializes the AFE and places it into a power-down state. All non-essential circuits are deactivated and the D<sub>E</sub> and VF<sub>D</sub>O outputs are put in high impedance states. To power-up the device, a logical low level or clock must be applied to the MCLK<sub>D</sub>/PDN pin and FS<sub>E</sub> and/or FS<sub>D</sub> pulses must be present. Thus, 2 power-down control modes are available. The first is to pull the MCLK<sub>D</sub>/PDN pin high; the alternative is to hold both FS<sub>E</sub> and FS<sub>D</sub> inputs continuously low—the device will power-down approximately 2 ms after the last FS<sub>E</sub> or FS<sub>D</sub> pulse. Power-up will occur on the first FS<sub>E</sub> or FS<sub>D</sub> pulse. The TRI-STATE data output, D<sub>E</sub>, will remain in the high impedance state until the second FS<sub>E</sub> pulse.

### SYNCHRONOUS OPERATION

For synchronous operation, the same master clock and bit clock should be used for both the encode and decode directions. In this mode, a clock must be applied to MCLK<sub>E</sub> and the MCLK<sub>D</sub>/PDN pin can be used as a power-down control. A low level on MCLK<sub>D</sub>/PDN powers up the device and a high level powers down the device. In either case, MCLK<sub>E</sub> will be selected as the master clock for both the encode and decode circuits. A bit clock must also be applied to BCLK<sub>E</sub>

and the BCLK<sub>D</sub>/CLKSEL can be used to select the proper internal divider for a master clock of 1.536 MHz, 1.544 MHz or 2.048 MHz. For 1.544 MHz operation, the device automatically compensates for the 193rd clock pulse each frame.

With a fixed level on the BCLK<sub>D</sub>/CLKSEL pin, BCLK<sub>E</sub> will be selected as the bit clock for both the encode and decode directions. Table 1 indicates the frequencies of operation which can be selected, depending on the state of BCLK<sub>D</sub>/CLKSEL. In this synchronous mode, the bit clock, BCLK<sub>E</sub>, may be from 64 kHz to 2.048 MHz, but must be synchronous with MCLK<sub>E</sub>.

Each FS<sub>E</sub> pulse begins the encoding cycle and the data from the previous encode cycle is shifted out of the enabled D<sub>E</sub> output on the positive edge of BCLK<sub>E</sub>. After 8-bit clock periods, the TRI-STATE D<sub>E</sub> output is returned to a high impedance state. With an FS<sub>D</sub> pulse, data is latched via the D<sub>D</sub> input on the negative edge of BCLK<sub>E</sub> (or BCLK<sub>D</sub> if running). FS<sub>E</sub> and FS<sub>D</sub> must be synchronous with MCLK<sub>E</sub>/D.

TABLE 1. Selection of Master Clock Frequencies

BCLK <sub>D</sub> /CLKSEL	Master Clock Frequency Selected
	TP5510
Clocked	1.536 MHz or 1.544 MHz
0	2.048 MHz
1	1.536 MHz or 1.544 MHz

### ASYNCHRONOUS OPERATION

For asynchronous operation, separate encode and decode clocks may be applied. MCLK<sub>E</sub> and MCLK<sub>D</sub> must be 1.536 MHz or 1.544 MHz for the TP5510, and need not be synchronous. For best transmission performance, however, MCLK<sub>D</sub> should be synchronous with MCLK<sub>E</sub>, which is easily achieved by applying only static logic levels to the MCLK<sub>D</sub>/PDN pin. This will automatically connect MCLK<sub>E</sub> to all internal MCLK<sub>D</sub> functions (see Pin Description). For 1.544 MHz operation, the device automatically compensates for the 193rd clock pulse each frame. FS<sub>E</sub> starts each A/D conversion cycle and must be synchronous with MCLK<sub>E</sub> and BCLK<sub>E</sub>. FS<sub>D</sub> starts each D/A conversion cycle and must be synchronous with BCLK<sub>D</sub>. BCLK<sub>D</sub> must be a clock, the logic levels shown in Table 1 are not valid in asynchronous mode. BCLK<sub>E</sub> and BCLK<sub>D</sub> may operate from 64 kHz to 2.048 MHz.

### SHORT FRAME SYNC OPERATION

The AFE can utilize either a short frame sync pulse or a long frame sync pulse. Upon power initialization, the device assumes a short frame mode. In this mode, both frame sync pulses, FS<sub>E</sub> and FS<sub>D</sub>, must be one bit clock period long, with timing relationships specified in *Figure 2*. With FS<sub>E</sub> high during a falling edge of BCLK<sub>E</sub>, the next rising edge of BCLK<sub>E</sub> enables the D<sub>E</sub> TRI-STATE output buffer, which will output the sign bit. The following seven rising edges clock out the remaining seven bits, and the next falling edge disables the D<sub>E</sub> output. With FS<sub>D</sub> high during a falling edge of BCLK<sub>D</sub> (BCLK<sub>E</sub> in synchronous mode), the next falling edge of BCLK<sub>E</sub> latches in the sign bit. The following seven falling

## Functional Description (Continued)

edges latch in the seven remaining bits. Both devices may utilize the short frame sync pulse in synchronous or asynchronous operating mode.

### LONG FRAME SYNC OPERATION

To use the long frame mode, both the frame sync pulses,  $FS_E$  and  $FS_D$ , must be three or more bit clock periods long, with timing relationships specified in *Figure 3*. Based on the transmit frame sync,  $FS_E$ , the AFE will sense whether short or long frame sync pulses are being used. For 64 kHz operation, the frame sync pulse must be kept low for a minimum of 160 ns. The  $D_E$  TRI-STATE output buffer is enabled with the rising edge of  $FS_E$  or the rising edge of  $BCLK_E$ , whichever comes later, and the first bit clocked out is the sign bit. The following seven  $BCLK_E$  rising edges clock out the remaining seven bits. The  $D_E$  output is disabled by the falling  $BCLK_E$  edge following the eighth rising edge, or by  $FS_E$  going low, whichever comes later. A rising edge on the decode frame sync pulse,  $FS_D$ , will cause the data at  $D_D$  to be latched in on the next eight falling edges of  $BCLK_D$  ( $BCLK_E$  in synchronous mode). Both devices may utilize the long frame sync pulse in synchronous or asynchronous mode.

### ENCODE SECTION

The encode section input is an operational amplifier with provision for gain adjustment using two external resistors, see *Figure 4*. The low noise and wide bandwidth allow gains in excess of 20 dB across the audio passband to be realized. The op amp drives a unity-gain filter consisting of RC active pre-filter, followed by an eighth order switched-ca-

pacitor bandpass filter clocked at 256 kHz. The output of this filter directly drives the A/D sample-and-hold circuit. The A/D is of compressing type according to  $\mu$ -law coding conventions. A precision voltage reference is trimmed in manufacturing to provide an input overload ( $t_{MAX}$ ) of nominally 2.5V peak (See Table of Transmission Characteristics). The  $FS_E$  frame sync pulse controls the sampling of the filter output, and then the successive-approximation encoding cycle begins. The 8-bit code is then loaded into a buffer and shifted out through  $D_E$  at the next  $FS_E$  pulse. The total encoding delay will be approximately 165  $\mu$ s (due to the encode filter) plus 125  $\mu$ s (due to encoding delay), which totals 290  $\mu$ s. Any offset voltage due to the filters or comparator is cancelled by sign bit integration.

### DECODE SECTION

The decode section consists of an expanding DAC which drives a fifth order switched-capacitor low pass filter clocked at 256 kHz. The DAC is  $\mu$ -law and the 5th order low pass filter corrects for the  $\sin x/x$  attenuation due to the 8 kHz sample/hold. The filter is then followed by a 2nd order RC active post-filter/power amplifier capable of driving a 600 $\Omega$  load to a level of 7.2 dBm. The decode section is unity-gain. Upon the occurrence of  $FS_D$ , the data at the  $D_D$  input is clocked in on the falling edge of the next eight  $BCLK_D$  ( $BCLK_E$ ) periods. At the end of the DAC time slot, the D/A conversion cycle begins, and 10  $\mu$ s later the DAC output is updated. The total DAC delay is  $\sim 10$   $\mu$ s (DAC update) plus 110  $\mu$ s (filter delay) plus 62.5  $\mu$ s ( $1/2$  frame), which gives approximately 180  $\mu$ s.

## Absolute Maximum Ratings

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

$V_{CC}$ to GNDA	7V
$V_{BB}$ to GNDA	−7V
Voltage at any Analog Input or Output	$V_{CC} + 0.3V$ to $V_{BB} - 0.3V$

Voltage at any Digital Input or Output	$V_{CC} + 0.3V$ to $GNDA - 0.3V$
Operating Temperature Range	−25°C to +125°C
Storage Temperature Range	−65°C to +150°C
Lead Temperature (Soldering, 10 seconds)	300°C
ESD (Human Body Model)	2000V
Latch-Up Immunity	= 100 mA on any Pin

## Electrical Characteristics

Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for  $V_{CC} = 5.0V \pm 5\%$ ,  $V_{BB} = -5.0V \pm 5\%$ ;  $T_A = 0^\circ C$  to  $70^\circ C$  by correlation with 100% electrical testing at  $T_A = 25^\circ C$ . All other limits are assured by correlation with other production tests and/or product design and characterization. All signals referenced to GNDA. Typicals specified at  $V_{CC} = 5.0V$ ,  $V_{BB} = -5.0V$ ,  $T_A = 25^\circ C$ .

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>DIGITAL INTERFACE</b>						
$V_{IL}$	Input Low Voltage				<b>0.6</b>	V
$V_{IH}$	Input High Voltage		<b>2.2</b>			V
$V_{OL}$	Output Low Voltage	$D_E, I_L = 3.2\text{ mA}$ $SI_{GD}, I_L = 1.0\text{ mA}$ $TS_E, I_L = 3.2\text{ mA}$ , Open Drain			<b>0.4</b> <b>0.4</b> <b>0.4</b>	V V V
$V_{OH}$	Output High Voltage	$D_E, I_H = -3.2\text{ mA}$ $SI_{GD}, I_H = -1.0\text{ mA}$	<b>2.4</b> <b>2.4</b>			V V
$I_{IL}$	Input Low Current	$GNDA \leq V_{IN} \leq V_{IL}$ , All Digital Inputs	− <b>10</b>		<b>10</b>	$\mu A$
$I_{IH}$	Input High Current	$V_{IH} \leq V_{IN} \leq V_{CC}$	− <b>10</b>		<b>10</b>	$\mu A$
$I_{OZ}$	Output Current in High Impedance State (TRI-STATE)	$D_E, GNDA \leq V_O \leq V_{CC}$	− <b>10</b>		<b>10</b>	$\mu A$
<b>ANALOG INTERFACE WITH ENCODE INPUT AMPLIFIER (ALL DEVICES)</b>						
$I_{IEA}$	Input Leakage Current	$-2.5V \leq V \leq +2.5V$ , $VF_{EI}^+$ or $VF_{EI}^-$	− <b>200</b>		<b>200</b>	nA
$R_{IEA}$	Input Resistance	$-2.5V \leq V \leq +2.5V$ , $VF_{EI}^+$ or $VF_{EI}^-$	10			M $\Omega$
$R_{OEA}$	Output Resistance	Closed Loop, Unity Gain		1	3	$\Omega$
$R_{LEA}$	Load Resistance	$GS_E$	10			k $\Omega$
$C_{LEA}$	Load Capacitance	$GS_E$			50	pF
$V_{OEA}$	Output Dynamic Range	$GS_E, R_L \geq 10\text{ k}\Omega$	− <b>2.8</b>		<b>2.8</b>	V
$A_{VEA}$	Voltage Gain	$VF_{EI}^+$ to $GS_E$	<b>5000</b>			V/V
$F_{UEA}$	Unity Gain Bandwidth		1	2		MHz
$V_{OSEA}$	Offset Voltage		− <b>20</b>		<b>20</b>	mV
$V_{CMEA}$	Common-Mode Voltage	$CMRREA > 60\text{ dB}$	−2.5		2.5	V
$CMRREA$	Common-Mode Rejection Ratio	DC Test	60			dB
$PSRREA$	Power Supply Rejection Ratio	DC Test	60			dB
<b>ANALOG INTERFACE WITH DECODE FILTER (ALL DEVICES)</b>						
$R_{ODF}$	Output Resistance	Pin $VF_{DO}$		1	3	$\Omega$
$R_{LDF}$	Load Resistance	$VF_{DO} = \pm 2.5V$	600			$\Omega$
$C_{LDF}$	Load Capacitance				500	pF
$V_{OSDO}$	Output DC Offset Voltage		−200		200	mV
<b>POWER DISSIPATION (ALL DEVICES)</b>						
$I_{CC0}$	Power-Down Current	No Load (Note)		0.5	<b>3</b>	mA
$I_{BB0}$	Power-Down Current	No Load (Note)		0.05	<b>1</b>	mA
$I_{CC1}$	Power-Up Active Current	No Load		6.0	<b>12</b>	mA
$I_{BB1}$	Power-Up Active Current	No Load		6.0	<b>12</b>	mA

**Note:**  $I_{CC0}$  and  $I_{BB0}$  are measured after first achieving a power-up state.

## Timing Specifications

Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for  $V_{CC} = 5.0V \pm 5\%$ ,  $V_{BB} = -5.0V \pm 5\%$ ;  $T_A = 0^\circ C$  to  $70^\circ C$  by correlation with 100% electrical testing at  $T_A = 25^\circ C$ . All other limits are assured by correlation with other production tests and/or product design and characterization. All signals referenced to GND. Typical values specified at  $V_{CC} = 5.0V$ ,  $V_{BB} = -5.0V$ ,  $T_A = 25^\circ C$ . All timing parameters are measured at  $V_{OH} = 2.0V$  and  $V_{OL} = 0.7V$ . See Definitions and Timing Conventions section for test methods information.

Symbol	Parameter	Conditions	Min	Typ	Max	Units
$1/t_{PM}$	Frequency of Master Clocks	Depends on the Device Used and the BCLK <sub>D</sub> /CLKSEL Pin. MCLK <sub>E</sub> and MCLK <sub>D</sub>		1.536 1.544 <b>2.048</b>		MHz MHz MHz
$t_{DM}$	Rise Time of Master Clock	MCLK <sub>E</sub> and MCLK <sub>D</sub>			50	ns
$t_{FM}$	Fall Time of Master Clock	MCLK <sub>E</sub> and MCLK <sub>D</sub>			50	ns
$t_{PB}$	Period of Bit Clock		485	<b>488</b>	15725	ns
$t_{DB}$	Rise Time of Bit Clock	BCLK <sub>E</sub> and BCLK <sub>D</sub>			50	ns
$t_{FB}$	Fall Time of Bit Clock	BCLK <sub>E</sub> and BCLK <sub>D</sub>			50	ns
$t_{WMH}$	Width of Master Clock High	MCLK <sub>E</sub> and MCLK <sub>D</sub>	<b>160</b>			ns
$t_{WML}$	Width of Master Clock Low	MCLK <sub>E</sub> and MCLK <sub>D</sub>	<b>160</b>			ns
$t_{SBFM}$	Set-Up Time from BCLK <sub>E</sub> High to MCLK <sub>E</sub> Falling Edge	First Bit Clock after the Leading Edge of FS <sub>E</sub>	<b>100</b>			ns
$t_{SFFM}$	Set-Up Time from FS <sub>E</sub> High to MCLK <sub>E</sub> Falling Edge	Long Frame Only	<b>100</b>			ns
$t_{WBH}$	Width of Bit Clock High	$V_{IH} = 2.2V$	<b>160</b>			ns
$t_{WBL}$	Width of Bit Clock Low	$V_{IL} = 0.6V$	<b>160</b>			ns
$t_{HBFL}$	Holding Time from Bit Clock Low to Frame Sync	Long Frame Only	<b>0</b>			ns
$t_{HBFS}$	Holding Time from Bit Clock High to Frame Sync	Short Frame Only	<b>0</b>			ns
$t_{SFB}$	Set-Up Time from Frame Sync to Bit Clock Low	Long Frame Only	<b>115</b>			ns
$t_{DBD}$	Delay Time from BCLK <sub>E</sub> High to Data Valid	Load = 150 pF plus 2 LSTTL Loads	0		140	ns
$t_{DBTS}$	Delay Time to TS <sub>E</sub> Low	Load = 150 pF plus 2 LSTTL Loads			140	ns
$t_{DZC}$	Delay Time from BCLK <sub>E</sub> Low to Data Output Disabled	$C_L = 0$ pF to 150 pF	50		165	ns
$t_{DZF}$	Delay Time to Valid Data from FS <sub>E</sub> or BCLK <sub>E</sub> , Whichever Comes Later	$C_L = 0$ pF to 150 pF	20		165	ns
$t_{SDB}$	Set-Up Time from D <sub>D</sub> Valid to BCLK <sub>D/E</sub> Low		<b>50</b>			ns
$t_{HBD}$	Hold Time from BCLK <sub>D/E</sub> Low to D <sub>D</sub> Invalid		<b>50</b>			ns
$t_{SF}$	Set-Up Time from FS <sub>E/D</sub> to BCLK <sub>E/D</sub> Low	Short Frame Sync Pulse (1 Bit Clock Period Long)	<b>50</b>			ns
$t_{HF}$	Hold Time from BCLK <sub>E/D</sub> Low to FS <sub>E/D</sub> Low	Short Frame Sync Pulse (1 Bit Clock Period Long)	<b>100</b>			ns
$t_{HBF}$	Hold Time from 3rd Period of Bit Clock Low to Frame Sync (FS <sub>E</sub> or FS <sub>D</sub> )	Long Frame Sync Pulse (from 3 to 8 Bit Clock Periods Long)	<b>100</b>			ns
$t_{WFL}$	Minimum Width of the Frame Sync Pulse (Low Level)	64k Bit/s Operating Mode	<b>160</b>			ns

## Timing Diagrams

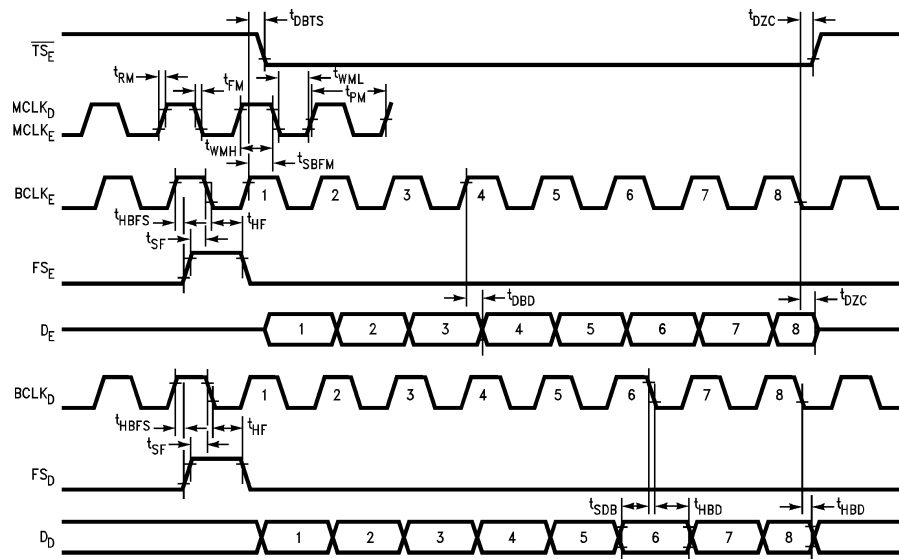


FIGURE 2. Short Frame Sync Timing

TL/H/11186-3

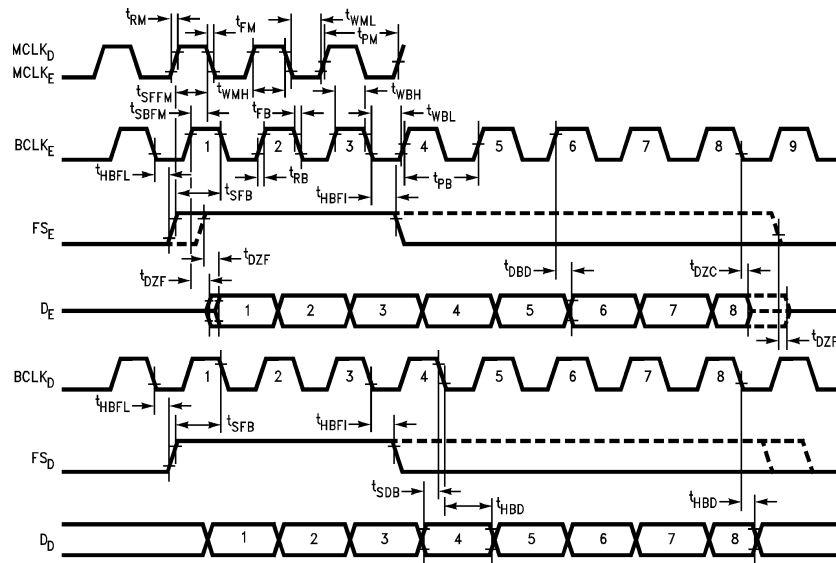


FIGURE 3. Long Frame Sync Timing

TL/H/11186-4

## Transmission Characteristics

Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for  $V_{CC} = 5.0V \pm 5\%$ ,  $V_{BB} = -5.0V \pm 5\%$ ;  $T_A = 0^\circ C$  to  $70^\circ C$  by correlation with 100% electrical testing at  $T_A = 25^\circ C$ . All other limits are assured by correlation with other production tests and/or product design and characterization.  $G_{NDA} = 0V$ ,  $f = 1.02$  kHz,  $V_{IN} = 0$  dBm0, encode input amplifier connected for unity gain non-inverting. Typicals specified at  $V_{CC} = 5.0V$ ,  $V_{BB} = -5.0V$ ,  $T_A = 25^\circ C$ .

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>AMPLITUDE RESPONSE</b>						
	Absolute Levels (Definition of Nominal Gain)	Nominal 0 dBm0 Level is 4 dBm (600 $\Omega$ ) 0 dBm0		1.2276		V <sub>rms</sub>
$t_{MAX}$	Max Overload Level	TP5510, (3.17 dBm0)		2.501		V <sub>PK</sub>
$G_{EA}$	Encode Gain, Absolute	$T_A = 25^\circ C$ , $V_{CC} = 5V$ , $V_{BB} = -5V$ Input at $G_{SE} = 0$ dBm0 at 1020 Hz	<b>-0.5</b>		<b>0.5</b>	dB
$G_{ER}$	Encode Gain, Relative to $G_{EA}$	f = 16 Hz f = 50 Hz f = 60 Hz f = 200 Hz f = 300 Hz – 3000 Hz f = 3400 Hz f = 4000 Hz f = 4600 Hz and Up, Measure Response from 0 Hz to 4000 Hz	<b>-2.0</b> <b>-0.5</b> <b>-1.5</b>		-35 -25 <b>-21</b> -0.1 <b>0.15</b> <b>0.5</b> <b>-10</b> <b>-25</b>	dB dB dB dB dB dB dB dB
$G_{EAT}$	Absolute Encode Gain Variation with Temperature	Relative to $G_{EA}$	-0.3		0.3	dB
$G_{ERL}$	Encode Gain Variations with Level	Sinusoidal Test Method Reference Level = -10 dBm0 $V_{FEI}^+ = -40$ dBm0 to +3 dBm0 $V_{FEI}^+ = -50$ dBm0 to -40 dBm0	<b>-0.4</b> <b>-0.8</b>		<b>0.4</b> <b>0.8</b>	dB dB
$G_{DA}$	Decode Gain, Absolute	$T_A = 25^\circ C$ , $V_{CC} = 5V$ , $V_{BB} = -5V$ Input = Digital Code Sequence for 0 dBm0 Signal at 1020 Hz	<b>-0.5</b>		<b>0.5</b>	dB
$G_{DR}$	Decode Gain, Relative to $G_{DA}$	f = 0 Hz to 3000 Hz f = 3400 Hz f = 4000 Hz	<b>-0.5</b> <b>-1.5</b>		<b>0.5</b> <b>0.5</b> <b>-14</b>	dB dB dB
$G_{DAT}$	Absolute Decode Gain Variation with Temperature	Relative to $G_{DA}$	-0.3		0.3	dB
$G_{DAV}$	Absolute Decode Gain Variation with Supply Voltage	Relative to $G_{DA}$	<b>-0.05</b>		<b>0.05</b>	dB
$G_{DRL}$	Decode Gain Variations with Level	Sinusoidal Test Method; Reference Input PCM Code Corresponds to an Ideally Encoded PCM Level = -40 dBm0 to +3 dBm0 = -50 dBm0 to -40 dBm0 = -55 dBm0 to -50 dBm0	<b>-0.4</b> <b>-0.8</b> <b>-2.5</b>		<b>0.4</b> <b>0.8</b> <b>2.5</b>	dB dB dB
$V_{DO}$	Decode Output Drive Level	$R_L = 600\Omega$	-2.5		2.5	V



**Transmission Characteristics** Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for  $V_{CC} = 5.0V \pm 5\%$ ,  $V_{BB} = -5.0V \pm 5\%$ ;  $T_A = 0^\circ C$  to  $70^\circ C$  by correlation with 100% electrical testing at  $T_A = 25^\circ C$ . All other limits are assured by correlation with other production tests and/or product design and characterization.  $G_{NDA} = 0V$ ,  $f = 1.02$  kHz,  $V_{IN} = 0$  dBm0, encode input amplifier connected for unity gain non-inverting. Typicals specified at  $V_{CC} = 5.0V$ ,  $V_{BB} = -5.0V$ ,  $T_A = 25^\circ C$ . (Continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>NOISE</b>						
$N_{EC}$	Encode Noise, C Message Weighted	TP5510 (Note 1)		12	16	dBrnC0
$N_{DC}$	Decode Noise, C Message Weighted	Digital Code is Alternating Positive and Negative Zero —TP5510		8	11	dBrnC0
$N_{DS}$	Noise, Single Frequency	$f = 0$ kHz to 100 kHz, Loop Around Measurement, $V_{F_{EI}^+} = 0$ Vrms			-53	dBm0
$PPSR_E$	Positive Power Supply Rejection, Encode	$V_{F_{EI}^+} = -50$ dBm0 $V_{CC} = 5.0 V_{DC} + 100$ mVrms $f = 0$ kHz–50 kHz (Note 2)	<b>-30</b>			dB
$NPSR_E$	Negative Power Supply Rejection, Encode	$V_{F_{EI}^+} = -50$ dBm0 $V_{BB} = -5.0 V_{DC} + 100$ mVrms $f = 0$ kHz–50 kHz (Note 2)	<b>-30</b>			dB
$PPSR_D$	Positive Power Supply Rejection, Decode	PCM Code Equals Positive Zero $V_{CC} = 5.0 V_{DC} + 100$ mVrms Measure $V_{F_{D0}}$ $f = 0$ Hz–4000 Hz $f = 4$ kHz–50 kHz	<b>30</b> <b>30</b>			dB dB
$NPSR_D$	Negative Power Supply Rejection, Decode	PCM Code Equals Positive Zero $V_{BB} = -5.0 V_{DC} + 100$ mVrms Measure $V_{F_{D0}}$ $f = 0$ Hz–4000 Hz $f = 4$ kHz–50 kHz	<b>30</b> <b>30</b>			dB dB

## Transmission Characteristics

Unless otherwise noted, limits printed in **BOLD** characters are guaranteed for  $V_{CC} = 5.0V \pm 5\%$ ,  $V_{BB} = -5.0V \pm 5\%$ ;  $T_A = 0^\circ C$  to  $70^\circ C$  by correlation with 100% electrical testing at  $T_A = 25^\circ C$ . All other limits are assured by correlation with other production tests and/or product design and characterization.  $G_NDA = 0V$ ,  $f = 1.02$  kHz,  $V_{IN} = 0$  dBm0, encode input amplifier connected for unity gain non-inverting. Typicals specified at  $V_{CC} = 5.0V$ ,  $V_{BB} = -5.0V$ ,  $T_A = 25^\circ C$ . (Continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
SOS	Spurious Out-of-Band Signals at the Channel Output	Loop Around Measurement, 0 dBm0, 300 Hz to 3400 Hz Input Digital Code Applied at $D_D$ . 4600 Hz–7600 Hz 7600 Hz–8400 Hz 8400 Hz–100,000 Hz			–30 –30 –30 –30	dB dB dB dB

## DISTORTION

STD <sub>E</sub> STD <sub>D</sub>	Signal to Total Distortion Encode or Decode Half-Channel	Sinusoidal Test Method (Note 3) Level = 3.0 dBm0 = 0 dBm0 to –30 dBm0 = –40 dBm0	28 <b>30</b> <b>25</b>			dBC dBC dBC
SFD <sub>E</sub>	Single Frequency Distortion, Encode				– <b>41</b>	dB
SFD <sub>D</sub>	Single Frequency Distortion, Decode				– <b>41</b>	dB
IMD	Intermodulation Distortion	Loop Around Measurement, $V_{F_{Encode}} = -4$ dBm0 to –21 dBm0, Two Frequencies in the Range 300 Hz–3400 Hz			–35	dB

## CROSSTALK

CT <sub>E-D</sub>	Encode to Decode Crosstalk, 0 dBm0 Encode Level	$f = 300$ Hz–3400 Hz $D_D =$ Quiet Code		–90	–70	dB
CT <sub>D-E</sub>	Decode to Encode Crosstalk, 0 dBm0 Decode Level	$f = 300$ Hz–3400 Hz, $V_{F_E} =$ Multitone (Note 2)		–90	–70	dB

## Format at $D_E$ Output

	TP5510 $\mu$ -Law
$V_{IN}$ (at $GS_E$ ) = + Full-Scale	1 0 0 0 0 0 0 0 0
$V_{IN}$ (at $GS_E$ ) = 0V	$\begin{cases} 1 & 1 & 1 & 1 & 1 & 1 & 1 & 1 \\ 0 & 1 & 1 & 1 & 1 & 1 & 1 & 1 \end{cases}$
$V_{IN}$ (at $GS_E$ ) = – Full-Scale	0 0 0 0 0 0 0 0 0

## POWER SUPPLIES

All ground connections to each device should meet at a common point as close as possible to the GNDA pin. This

For best performance, if more than 1 AFE is on a card, the ground point of each AFE on a card should be connected to a common card ground in star formation, rather than via a ground bus.

This common ground point should be decoupled to  $V_{CC}$  and  $V_{BB}$  with 10  $\mu F$  capacitors.

**Top View Dimensions:**

- Overall Width: 10.10-10.50
- Pin Pitch: 0.050 (1.27)
- Pin Height: 0.3977-0.4133
- Pin 1 Identification: LEAD NO 1 IDENTIFICATION
- Pin 1 Position: 0.2914-0.2992 (7.4-7.6)
- Pin 8 Position: 0.3940-0.4190 (10.00-10.65)

**Table of Mechanical Properties:**

0.0138-0.0200 0.350-0.508 TYP	0.010 0.25	M	A	C	S	B
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**Side View Dimensions:**

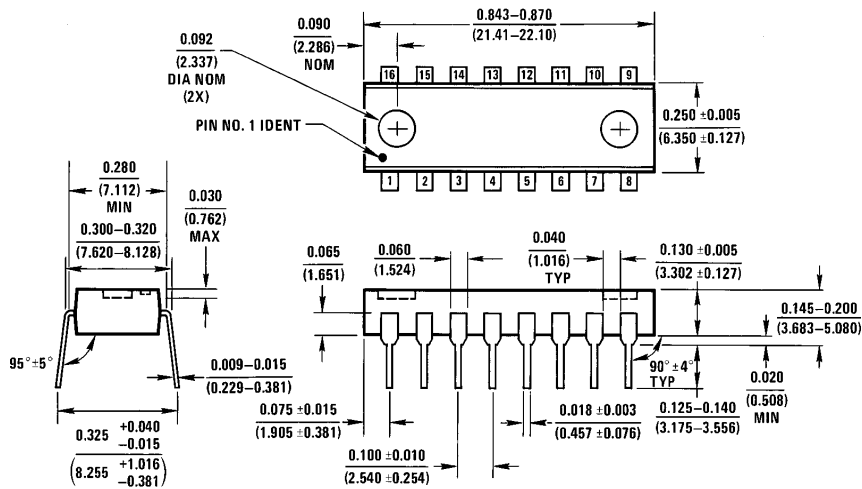
- Seating Plane: 0.014 (0.35)
- Overall Height: 2.35-2.65
- Pin Height: 0.0040-0.0118 (0.1-0.3)

**Lead Profile Dimensions:**

- Lead Height: 0.0091-0.0125 (0.23-0.32) TYP ALL LEADS
- Lead Width: 0.160-0.0500 (0.40-1.27) TYP ALL LEADS
- Lead Angle: 45° X 0.010-0.029 (0.25-0.75)
- Lead Tip: 0.004 (0.1) ALL LEAD TIPS
- Lead Profile: B MAX TYP ALL LEADS

**Molded Small Outline Package (WM)**  
**Order Number TP5510WM**  
**NS Package Number M16B**

## Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



N16A (REV E)

**Molded Dual-In-Line Package (N)**  
**Order Number TP5510N**  
**NS Package Number N16A**

### LIFE SUPPORT POLICY

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



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